


<b>Search Notes</b> 	<b>Application/Control No.</b> 10519988	<b>Applicant(s)/Patent Under Reexamination</b> SCHARNWEBER ET AL.
	<b>Examiner</b> Young J Kim	<b>Art Unit</b> 1637

SEARCHED			
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SEARCH NOTES		
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Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	2/27/2008	YJK
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Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	12/10/2008	/YJK/
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